

Notice of References Cited	Application/Control No. 10/539,975		Applicant(s)/Patent Under Reexamination DE VAAN ET AL.	
	Examiner PAULOS M. NATNAEL		Art Unit 2622	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,042,236	03-2000	Hatakeyama et al.	353/31
*	B	US-6,454,440	09-2002	Yamamoto, Chikara	362/293
*	C	US-6,626,540	09-2003	Ouchi et al.	353/31
*	D	US-5,808,759	09-1998	Okamori et al.	359/15
*	E	US-5,754,260	05-1998	Ooi et al.	349/10
*	F	US-6,862,047	03-2005	Hibi, Taketoshi	348/743
*	G	US-5,854,707	12-1998	Kasama et al.	359/487
*	H	US-5,661,608	08-1997	Barbier et al.	359/800
*	I	US-5,648,860	07-1997	Ooi et al.	349/10
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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